

Shu-Kai S Fan

List of Publications by Year in descending order

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40
papers

1,227
citations

516215

16
h-index

360668

35
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docs citations

40
times ranked

1051
citing authors

#	ARTICLE	IF	CITATIONS
1	Fault Diagnosis of Wafer Acceptance Test and Chip Probing Between Front-End-of-Line and Back-End-of-Line Processes. IEEE Transactions on Automation Science and Engineering, 2022, 19, 3068-3082.	3.4	15
2	Product-to-Product Virtual Metrology of Color Filter Processes in Panel Industry. IEEE Transactions on Automation Science and Engineering, 2022, 19, 3496-3507.	3.4	8
3	Data Visualization of Anomaly Detection in Semiconductor Processing Tools. IEEE Transactions on Semiconductor Manufacturing, 2022, 35, 186-197.	1.4	6
4	Key Feature Identification for Monitoring Wafer-to-Wafer Variation in Semiconductor Manufacturing. IEEE Transactions on Automation Science and Engineering, 2022, 19, 1530-1541.	3.4	6
5	Data-driven optimization of accessory combinations for final testing processes in semiconductor manufacturing. Journal of Manufacturing Systems, 2022, 63, 275-287.	7.6	6
6	A New Double Exponentially Weighted Moving Average Run-to-Run Control Using a Disturbance-Accumulating Strategy for Mixed-Product Mode. IEEE Transactions on Automation Science and Engineering, 2021, 18, 1846-1860.	3.4	17
7	Auto-Annotated Deep Segmentation for Surface Defect Detection. IEEE Transactions on Instrumentation and Measurement, 2021, 70, 1-10.	2.4	44
8	An Efficient No-Shutdown Pipe-Fixing Freezing Design for Water Management System in Hospitals during COVID-19: A Case Study. Water (Switzerland), 2021, 13, 2725.	1.2	1
9	A Review on Fault Detection and Process Diagnostics in Industrial Processes. Processes, 2020, 8, 1123.	1.3	112
10	Defective wafer detection using a denoising autoencoder for semiconductor manufacturing processes. Advanced Engineering Informatics, 2020, 46, 101166.	4.0	34
11	Data-Driven Approach for Fault Detection and Diagnostic in Semiconductor Manufacturing. IEEE Transactions on Automation Science and Engineering, 2020, 17, 1925-1936.	3.4	81
12	Key Parameter Identification and Defective Wafer Detection of Semiconductor Manufacturing Processes Using Image Processing Techniques. IEEE Transactions on Semiconductor Manufacturing, 2019, 32, 544-552.	1.4	14
13	An Enhanced Partial Search to Particle Swarm Optimization for Unconstrained Optimization. Mathematics, 2019, 7, 357.	1.1	31
14	Profile Monitoring for Autocorrelated Reflow Processes with Small Samples. Processes, 2019, 7, 104.	1.3	8
15	Special issue for the "Asia Pacific Industrial Engineering and Management Systems (APIEMS) 2016 Conference". Engineering Optimization, 2018, 50, 1097-1098.	1.5	0
16	Modeling computer recycling in Taiwan using system dynamics. Resources, Conservation and Recycling, 2018, 128, 167-175.	5.3	30
17	Using machine learning and big data approaches to predict travel time based on historical and real-time data from Taiwan electronic toll collection. Soft Computing, 2018, 22, 5707-5718.	2.1	56
18	Nonlinear fault detection of batch processes based on functional kernel locality preserving projections. Chemometrics and Intelligent Laboratory Systems, 2018, 183, 79-89.	1.8	21

#	ARTICLE	IF	CITATIONS
19	Automatic vision-based grain optimization and analysis of multi-crystalline solar wafers using hierarchical region growing. <i>Engineering Optimization</i> , 2017, 49, 617-632.	1.5	0
20	Modeling and monitoring the nonlinear profile of heat treatment process data by using an approach based on a hyperbolic tangent function. <i>Quality Engineering</i> , 2017, 29, 226-243.	0.7	6
21	Rainfall Threshold Assessment Corresponding to the Maximum Allowable Turbidity for Source Water. <i>Water Environment Research</i> , 2016, 88, 2285-2291.	1.3	2
22	Wafer fault detection and key step identification for semiconductor manufacturing using principal component analysis, AdaBoost and decision tree. <i>Journal of Industrial and Production Engineering</i> , 2016, 33, 151-168.	2.1	29
23	A new multi-objective particle swarm optimizer using empirical movement and diversified search strategies. <i>Engineering Optimization</i> , 2015, 47, 750-770.	1.5	21
24	Profile monitoring of reflow process using approximations of mixture second-order polynomials. <i>Journal of Chemometrics</i> , 2014, 28, 815-833.	0.7	7
25	A trust region-based approach to optimize triple response systems. <i>Engineering Optimization</i> , 2014, 46, 606-627.	1.5	4
26	An enhanced case-based diagnosis mechanism for abnormal production administration. <i>International Journal of Production Research</i> , 2013, 51, 3131-3142.	4.9	4
27	Nonlinear Profile Monitoring of Reflow Process Data Based on the Sum of Sine Functions. <i>Quality and Reliability Engineering International</i> , 2013, 29, 743-758.	1.4	25
28	An integrated advanced process control framework using run-to-run control, virtual metrology and fault detection. <i>Journal of Process Control</i> , 2013, 23, 933-942.	1.7	25
29	Robust Multivariate Control Chart for Outlier Detection Using Hierarchical Cluster Tree in SW2. <i>Quality and Reliability Engineering International</i> , 2013, 29, 971-985.	1.4	10
30	An upside-down normal loss function-based method for quality improvement. <i>Engineering Optimization</i> , 2012, 44, 935-945.	1.5	12
31	Prediction of time-varying metrology delay for dEWMA and RLS-LT controllers. <i>Journal of Process Control</i> , 2012, 22, 823-828.	1.7	3
32	Statistical monitoring of nonlinear profiles by using piecewise linear approximation. <i>Journal of Process Control</i> , 2011, 21, 1217-1229.	1.7	24
33	A new search procedure of steepest ascent in response surface exploration. <i>Journal of Statistical Computation and Simulation</i> , 2011, 81, 661-678.	0.7	6
34	A New Image Registration Method Using Intensity Difference Data on Overlapped Image. , 2010, , .		2
35	Using simulation techniques to determine optimal operational region for multi-responses problems. <i>International Journal of Production Research</i> , 2009, 47, 3219-3230.	4.9	9
36	AMSE optimal design using generalized estimation for multi-factor response surfaces. <i>Journal of Chemometrics</i> , 2007, 21, 126-132.	0.7	0

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37	A hybrid simplex search and particle swarm optimization for unconstrained optimization. European Journal of Operational Research, 2007, 181, 527-548.	3.5	298
38	Optimal multi-thresholding using a hybrid optimization approach. Pattern Recognition Letters, 2005, 26, 1082-1095.	2.6	124
39	Hybrid simplex search and particle swarm optimization for the global optimization of multimodal functions. Engineering Optimization, 2004, 36, 401-418.	1.5	123
40	Implementation of ridge analysis on quadratic response surfaces. Journal of Statistical Computation and Simulation, 2003, 73, 675-684.	0.7	3